

2nd KJICT WS (Korea/Japan Industrial CT Workshop)

Organized by Japan Society of Precision Engineering Special Interest Group on Convergence Engineering (GENBUTSU YUGO-GATA ENGINEERING)

Workshop Chair: Hiromasa SUZUKI, The University of Tokyo, JAPAN

June 10th and 11th

The University of Tokyo, Tokyo, JAPAN

Hongo 7-3-1, Bunkyo, Tokyo 113-8656, JAPAN

Industrial Computed Tomography has gained more attention these days but the opportunity is still limited for Asian researchers and engineers to gather to discuss their recent developments. *KJICT WS (Korea/Japan Industrial Computed Tomography Workshop)* is organized by the collaboration of Korean and Japanese researchers aiming at start-up of the future full-fledged events. The 1st KJICT was held at Korea Institute of Industrial Technology in Korea, 2014. This year the 2nd workshop will be held at The University of Tokyo, Japan. The core members of the workshop will make eight presentations at the workshop. We would call for general participation to the workshop.

WORKSHOP PROGRAM

DAY 1 (June 10th, 2015)

Room 142, Engineering Building #14, The University of Tokyo

14:00-14:10 Opening

14:10-15:30 ORAL PRESENTATION (1) Chair: Yutaka Ohtake (UTokyo)

- Geometrical errors detection of dimensional X-ray computed tomography using calibrated gauges
Osamu Sato (AIST)*, Kazuya Matsuzaki (AIST), Hiroyuki Fujimoto (AIST), Makoto Abe (AIST) and Toshiyuki Takatsuji (AIST)
- Comparison of measurement performance verification method for dimensional X-ray CT
Kazuya Matsuzaki (AIST)*, Osamu Sato (AIST), Hiroyuki Fujimoto (AIST), Makoto Abe (AIST) and Toshiyuki Takatsuji (AIST)
- Evaluation of effectiveness of casting defect on physical properties for die cast by using 3D computed tomography
In-Sung Cho (KITECH)*, Si-Young Kwak (KITECH), Min-Joo Oh (KITECH), Sung-Chul Jang (UST) and Chae-Ho Lim (KITECH)
- Geometry improvement of industrial CT mesh using laser scanned point cloud
Tae-wan Kim (SNU)*, Wonchul Yoo (SNU) and WangSeok Jang (SNU)

<10 min Break>

15:40-17:00 ORAL PRESENTATION (2) Chair: Kenneth Kim (3DII)

- A method for improving measurement accuracy of cylinders in dimensional CT metrology
Lin Xue (UTokyo)*, Hiromasa Suzuki (UTokyo), Yutaka Ohtake (UTokyo), Hiroyuki Fujimoto (AIST), Makoto Abe (AIST) and Toshiyuki Takatsuji (AIST)
- Detection of internal defect of CMC from CT image
Yu Hasegawa (UTokyo), Yukie Nagai (UTokyo)*, Hiromasa Suzuki (UTokyo), Yutaka Ohtake (UTokyo), Hiroyuki Hishida (IHI), Koichi Inagaki (IHI) and Takeshi Nakamura (IHI)
- Segmentation of machine parts using rigid registration and template matching in industrial CT images
YongGeun Lee (SNU)* and Minyoung Chung (SNU)
- Introduction of 3DII's voxel solutions
DongJoon Kim (3DII)*, Kenneth Kim (3DII), SeongTae Kang (3DII) and SungChul Jang (3DII)

17:30-18:00 Laboratory Tour (SIP Delight Design Project, Suzuki Ohtake Lab)

DAY 2 (June 11th, 2015)

TECHNICAL VISITS (Invitation Only)

Morning Development of dimensional XCT

Research Institute for Engineering Measurement, National Metrology Institute of Japan (NMIJ),
National Institute of Advanced Industrial Science and Technology (AIST)
1-1-1, Umezono, Tsukuba, Ibaraki 305-8568, Japan

Afternoon Development of high-energy XCT

Hitachi Ltd. Katsuta Plant
832-2, Hitachi-Naka, Ibaraki 312-0034, Japan

Acronym

SNU = Seoul National University
KITECH = Korea Institute of Industrial Technology
3DII = 3D Industrial Imaging
UST = University of Science and Technology
AIST = National Institute of Advanced Industrial Science and Technology
IHI = IHI Corporation
UTokyo = The University of Tokyo

Contact

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Osamu Sato, Senior Researcher, AIST, Japan (osm-satou@aist.go.jp)

* is added to a speaker.